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**Optical properties of few-layer MoS<sub>2</sub>-based heterostructures**

ASMA ALKABSH, HASSANA SAMASSEKOU, ANDREW WALKER, DIPANJAN MAZUMDAR, SAIKAT TALAPATRA, Southern IL Univ-Carbondale — 2D materials such as Transition metal dichalcogenides (TMDs) are promising for a number of electronic/optoelectronic applications. In particular, semiconducting MoS<sub>2</sub>, is considered as one of the most interesting 2D material due to its direct band gap at the monolayer level [1]. For device applications, such desirable properties have to translate when MoS<sub>2</sub> is layered with other materials and substrates. In this research, the optical properties of select MoS<sub>2</sub>-based heterostructures are investigated. In particular, the effect of various insulating underlayers such as BN, SiO<sub>2</sub> on few-layer MoS<sub>2</sub> are examined using spectroscopic ellipsometry. The angles  $\Psi$  and  $\Delta$ , as well as layer specific optical constants such as extinction coefficient ( $k$ ) and refractive index ( $n$ ) shall be extracted using Tauc-Lorentz oscillator model and as a function of MoS<sub>2</sub> layer thickness and underlayer structure. The band gap properties of few-layer MoS<sub>2</sub> will be analyzed using optical spectroscopy

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